

**Notice of References Cited**

Application/Control No.

10/596,044

Applicant(s)/Patent Under  
Reexamination  
RENAUD ET AL.

Examiner

Anh T. Mai

Art Unit

2832

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N	JP 59144105 A	08-1984	Japan	ARAKAWA et al.	
	O					
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**NON-PATENT DOCUMENTS**

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